



Magnetic and structural properties of epitaxial Fe thin films on GaAs(0 0 1) and interfaces

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Abstract

Fe(001) thin films (70 Å) with ⁵⁷Fe(7.2 Å) tracer layers at the interface were epitaxially grown on GaAs(4 × 6) surfaces. Magneto-optic Kerr effect and Ferromagnetic resonance measurements indicate a dominant 2-fold in-plane magnetic anisotropy (easy axis along [1 1 0]) superimposed to a 4-fold anisotropy, and small coercivity (~10 Oe). Mössbauer (CEMS) measurements indicate no magnetic “dead layer” and an average Fe moment of ~1.7–2 μ_B at the Fe/GaAs interface. © 2002 Elsevier Science B.V. All rights reserved.

Keywords: Iron/gallium arsenide; Magneto-optic Kerr effect; Ferromagnetic resonance; Mössbauer effect; Reflection high-energy electron diffraction

Magnetic films epitaxially grown on semiconducting substrates have a high potential for technical applications (see for instance Ref. [1]). For this purpose knowledge of the state of the interface is important. It was demonstrated recently by magnetometry that low-temperature growth of Fe on (Ga-terminated) GaAs(001)(4 × 6) surfaces inhibits magnetic “dead layer” formation [2,3], or creates half-magnetization phases due to atomic intermixing at the interface [4]. In our present study Mössbauer spectroscopy (CEMS) on thin interfacial ⁵⁷Fe-isotope probe layers was employed, combined with Reflection high-energy electron diffraction (RHEED), Magneto-optic Kerr effect (MOKE) and Ferromagnetic resonance (FMR).

An MBE system (base pressure 9×10^{-11} mbar) was used to prepare the samples. The substrates were cleaned by Ar⁺ sputtering (0.5 keV) at 600°C for 30 min. After this, in-situ RHEED images of the substrate (Fig. 1(a)) revealed the pseudo (4 × 6) surface reconstruction, characteristic of the clean flat Ga-terminated GaAs(001)

surface [2]. Then we deposited 7.2 Å (5 monolayers, ML) of 95% enriched ⁵⁷Fe isotope, followed by 70 Å of natural Fe (deposition pressure: $< 2 \times 10^{-10}$ mbar; rate: 0.03 Å/s). The substrate temperature was 40–50°C during deposition. The samples were coated by 40 Å of Sn for protection.

After deposition of 5 ML of ⁵⁷Fe and above, the spotty fundamental reflections in the RHEED patterns (Fig. 1(b) and (c)) are typical for epitaxial BCC-Fe(001) 3D island growth. From the separation of the reflections in reciprocal space the relative Fe in-plane atomic distance during growth has been determined (Fig. 1(d)). After an initial strong increase which we ascribe to initial intermixing of the interface during island growth, the in-plane atomic distance above ~5 ML thickness remains ~1.3% larger than that of GaAs. This agrees with Ref. [2] and with the lattice mismatch between bulk BCC Fe and GaAs of 1.38%. We conclude that the epitaxial Fe films are not significantly strained in-plane.

The observed CEM spectrum (Fig. 2) was least-squares fitted with two subspectra: a sextet with sharp lines and a magnetic hyperfine (hf) field of 32.8 T due to “bulk-like” BCC Fe, and a broad sextet with a distribution of hf fields, $P(B_{hf})$, ascribed to a concentra-

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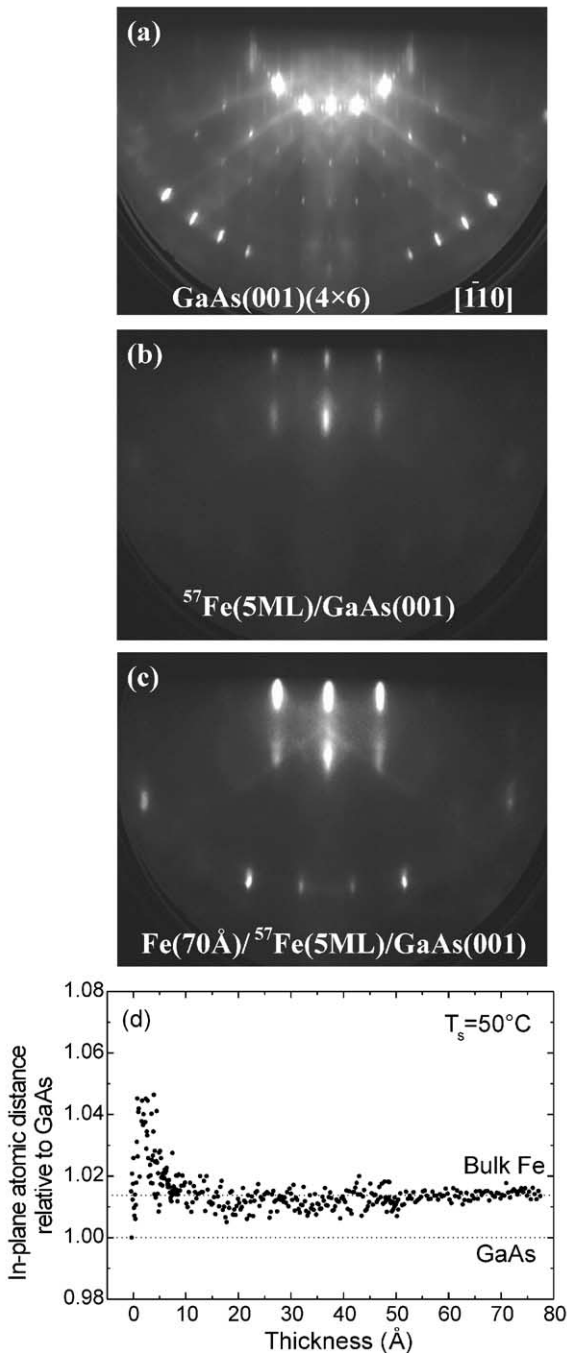


Fig. 1. RHEED patterns (10 kV, along [1-10] azimuth) of clean GaAs(001)(4 × 6) substrate (a), covered by 5 ML (7.2 Å) of ^{57}Fe (b), followed by 70 Å of natural Fe (c), in-plane atomic distance (relative to GaAs) versus Fe film thickness (d).

tion gradient (very likely of Ga atoms in an Fe-rich Fe–Ga alloy) at the intermixed Fe/GaAs interface. Since a peak at 0 T is not observed in $P(B_{\text{hf}})$, a magnetic dead layer does not exist at the interface. Moreover, the most

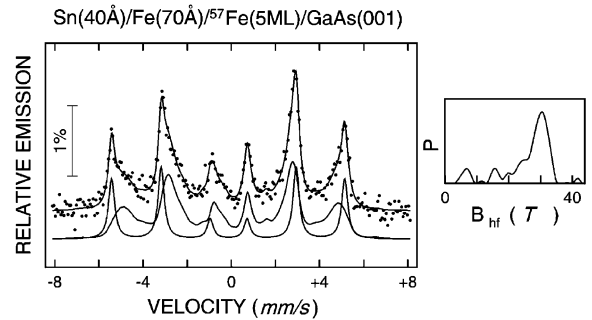


Fig. 2. Mössbauer spectrum (CEMS) and hyperfine magnetic field distribution (on the right).

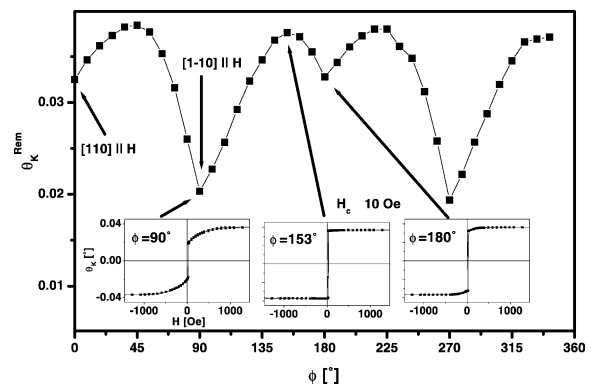


Fig. 3. Kerr-rotation angle θ_K^{Rem} measured at remanence versus the in-plane rotation angle ϕ . Inserts: typical Kerr hysteresis loops at specific ϕ values. At $\phi = 0^\circ$ (90°) B_{ext} is along the [1 1 0] direction ([1 -1 0] direction) of the substrate.

probable and average hf field in the distribution are 30.5 and 26.0 T, respectively. By using the usual conversion factor of $15 \text{ T}/\mu_B$ we deduce corresponding Fe atomic moments of ~ 2 and $\sim 1.7 \mu_B$, respectively. Thus the interface contains high Fe moments, and large hf fields, similar to those in ferromagnetic Fe–Ga alloys [6].

Magnetic hysteresis curves were measured using longitudinal MOKE with different in-plane rotational angles ϕ between the in-plane applied field H and the in-plane crystallographic axes of the substrate (Fig. 3, inserts). The remanence plotted versus the angle ϕ (Fig. 3) indicates the superposition of a dominant in-plane 2-fold (uniaxial) magnetic anisotropy and a weaker in-plane 4-fold anisotropy. The 2-fold anisotropy has easy axes along the [1 1 0] direction of the substrate (hard axes along [1 -1 0]). The 4-fold anisotropy has easy directions at $\phi \approx 45^\circ, 135^\circ, 225^\circ$ and 315° . The origin of the 4-fold anisotropy is the crystalline anisotropy of BCC–Fe, while the uniaxial anisotropy is due to interface anisotropy [5]. The small coercive field of $\sim 10 \text{ Oe}$ indicates good crystalline film quality.

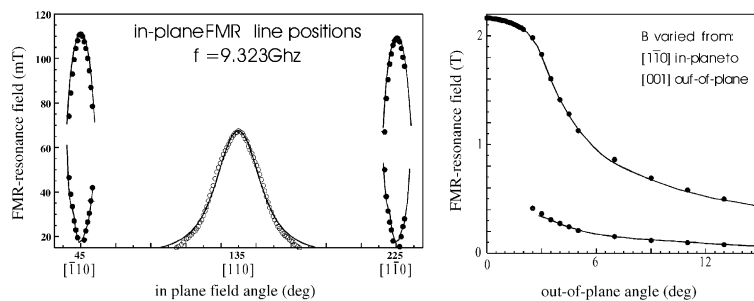


Fig. 4. Angular dependence of FMR line position: dependence on external field angle in the Fe(001) film plane (left) and dependence on out-of-plane external field angle in the (110) plane (right).

Our angle dependent FMR investigations yield the following magnetic anisotropy fields [7]: $B_{\text{eff}} = \mu_0 M - 2K_s/tM = 1.9\text{ T}$, $K_1/M = 19.4\text{ mT}$, $K_{1s}/M = 13\text{ mT}$, $K_u/M = 11.2\text{ mT}$, and $g\text{-factor} = 2.09$. (M is saturation magnetization, t Fe film thickness, K_s surface anisotropy, K_1 in-plane crystalline anisotropy, K_{1s} out-of-plane crystalline anisotropy due to tetragonal distortion, K_u in-plane uniaxial anisotropy.) In order to obtain these parameters FMR was performed with the external field B_{ext} oriented either in the (001) plane (Fe film surface), the (1-10) plane, or in the (-1-10) plane. In Fig. 4 (left) the measured FMR-line position is plotted versus the in-plane B_{ext} angle in the (001)-Fe plane. One can clearly distinguish the influence of the 4-fold in-plane crystalline anisotropy and the 2-fold uniaxial in-plane anisotropy. The uniaxial hard axis is oriented along $[-110]$ and $[1-10]$, and the uniaxial easy axis is along $[110]$, in agreement with our MOKE results. A peculiarity of FMR at 9.325 GHz on epitaxial Fe films is the observation of two lines for certain B_{ext} orientations (for details see Ref. [7]). In Fig. 4 (right) the FMR line position is plotted versus the out-of-plane B_{ext} angle. At about 3° (i.e. close to the film normal direction) the position of both lines is extremely

sensitive to a tetragonal distortion of Fe described by K_{1s} .

Work supported by Deutsche Forschungsgemeinschaft (SFB 491)

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